Ref #	Hits	Search Query	DBs	Default Operat or	Plura Is	Time Stamp
	16922	((382/100,232,240) or (380/51,54,201,210,252, 287) or (370/522,523,524, 525,526,527,528,529) or (713/176,179) or (348/461,463) or (725/9, 20,22) or (283/72,74,75, 76,77,78,79,80,81,85,93, 113,901,902) or (375/130)).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/18 08:46
L3	11031	1 and (detect\$4 or recogni\$4 or scan\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:53
L4	2227	3 and (watermark\$4 or steganograph\$4 or invisibl\$4 or water-mark\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:00
L5	2029	4 and (imag\$3 or video\$3)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:48

L6	1614	5 and block\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:48
L7	1252	6 and compar\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:01
L8	415	7 and probabilit\$5	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:54
L9	394	8 and select\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:50
L11	40	9 and diagonal\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:13

L12	118985	((detect\$4 or recogni\$4 or scan\$4) near4 (block\$3))	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:55
L13	2542	12 and (watermark\$4 or steganograph\$4 or invisibl\$4 or water-mark\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:54
L14	521	13 and probabilit\$5	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:01
L15	478	14 and compar\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 08:54
L16	24	15 and (((select\$4) near4 (detect\$4 or recogni\$4 or scan\$4) near4 (block\$3)))	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:00

L17	70	1 and (((select\$4) near4 (detect\$4 or recogni\$4 or scan\$4) near4 (block\$3)))	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:00
L18	30	17 and (watermark\$4 or steganograph\$4 or invisibl\$4 or water-mark\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:00
L19	19	18 and probabilit\$5	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:11
L20	19	19 and compar\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:10
L21 \	1	1 and city-block\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:10

L22	27	18 and threshold\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:11
L23	19	22 and overlap\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:13
L24	1	23 and (minimum near4 distanc\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:12
L25	125	13 and (minimum near4 distanc\$4)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:12
L26	96	25 and overlap\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:13

L27	26	26 and diagonal\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:14
L28	7	1 and 27	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/05/18 09:14



Home | Legin | Legisif | Access information | Alc

Welcome United States Patent and Trademark Office

Search Results

BROWSE

SEARCH

IEEE XPLORE GUIDE

Results for "((watermark	′ <and> probabilit*</and>	<and> detect*</and>	<and> block*</and>	') <in>metadata)"</in>
Your search matched 5 of	1160635 document	ts.		

⊠ e-mail

New Search	h						
» Кеу		Mod m	/ Search				
		((wate	rmark* <and> probabilit* <and> detect* <and> block*)<in> metadata)</in></and></and></and>				
ieee jnl	IEEE Journal or Magazine	П	Check to search only within this results set				
iee Jnl	IEE Journal or Magazine	Displa	Display Format: © Citation © Citation & Abstract				
SEEE CAF	IEEE Conference Proceeding						
iee Cnf	IEE Conference Proceeding	Select	Article information				
EEE STD	IEEE Standard `		 DCT-domain watermarking techniques for still images: detector performance analysis and a new struthernandez, J.R., Amado, M., Perez-Gonzalez, F., Image Processing, IEEE Transactions on Volume 9, Issue 1, Jan. 2000 Page(s):55 - 68 				
			AbstractPlus References Full Text: PDF(596 KB) RESE JAL				
			2. Hierarchical watermarking scheme for image authentication and recovery Phen-Lan Lin; Chung-Kai Hsieh; Po-Whei Huang; Multimedia and Expo, 2004. ICME '04. 2004 IEEE International Conference on Volume 2, 27-30 June 2004 Page(s):963 - 966 Vol.2				
			AbstractPlus Full Text: PDF(589 KB) IESE CNF				
			3. Image watermarking using DCT domain constraints Bors, A.G.; Pitas, I.; Image Processing, 1996. Proceedings., International Conference on Volume 3, 16-19 Sept. 1996 Page(s):231 - 234 vol.3				
			AbstractPlus Full Text: PDF(576 KB) 経路部で対す				
		n	4. Adaptive watermarking in the DCT domain Tao, B.; Dickinson, B.; Acoustics, Speech, and Signal Processing, 1997. ICASSP-97., 1997 IEEE International Conference on Volume 4, 21-24 April 1997 Page(s):2985 - 2988 vol.4				
	•		AbstractPlus Full Text: PDF(328 KB) IEEE CNF				
			 Reliable communication over channels with insertions, deletions, and substitutions Davey, M.C.; Mackay, D.J.C.; Information Theory, IEEE Transactions on Volume 47, Issue 2, Feb 2001 Page(s):687 - 698 				
			AbstractPlus References Full Text: PDE(304 KB) IEEE JRIL				

Help Contact Us Privac

© Copyright 2006 (€

indexed by #Inspec

⊠e-mail



IEE Conference

Proceeding

IEEE Standard

Home | Legin | Legour | Access information | Alc

Welcome United States Patent and Tradenark Office

Search Results

BROWSE

1. Image watermarking using DCT domain constraints

Volume 3, 16-19 Sept. 1996 Page(s):231 - 234 vol.3 AbstractPlus | Full Text: PDF(576 KB) NEEL CNF

Image Processing, 1996. Proceedings., International Conference on

SEARCH

IEEE XPLORE GUIDE

Results for "((watermark* <and> probabilit* <and> detect* <and> block* <and> select*)<..." Your search matched 1 of 1160635 documents. A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order. View Session History » New Search Modify Search » Key ((watermark* <and> probabilit* <and> detect* <and> block* <and> select*)<in>metad IEEE Journal or EEE JNL Check to search only within this results set Magazine IEE Journal or HEE JNL Display Format: Citation Citation & Abstract HEEE CHE IEEE Conference

Bors, A.G.; Pitas, I.;

Contact Us Privac

© Copyright 2006 III

inspec

HEE CNF

ieee std